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Equation (2) in the original article<sup>1</sup> was incorrect. The correct equation should read

$$\delta f(k, A) = \sqrt{\frac{f_0 k_B T B}{\pi k Q A^2} + \frac{2n_{ds}^2 B^3}{3A^2}}. \quad (2)$$

This correction does not affect any other contents of the original article.

<sup>1</sup>Y. Hosokawa, K. Kobayashi, N. Oyabu, K. Matsushige, and H. Yamada, *Rev. Sci. Instrum.* **81**, 093701 (2010).

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